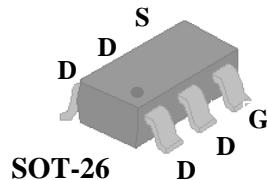




▼ Simple Drive Requirement

▼ Small Package Outline

▼ Surface Mount Device

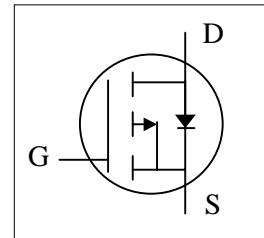


BV _{DSS}	-20V
R _{DS(ON)}	65mΩ
I _D	-5.0A

Description

Advanced Power MOSFETs utilized advanced processing techniques to achieve the lowest possible on-resistance, extremely efficient and cost-effectiveness device.

The SOT-26 package is widely used for all commercial-industrial applications.

**Absolute Maximum Ratings**

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	-20	V
V _{GS}	Gate-Source Voltage	+12	V
I _D @T _A =25°C	Continuous Drain Current, V _{GS} @ 4.5V ³	-5	A
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ 4.5V ³	-4	A
I _{DM}	Pulsed Drain Current ¹	-20	A
P _D @T _A =25°C	Total Power Dissipation	2	W
	Linear Derating Factor	0.016	W/°C
T _{STG}	Storage Temperature Range	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Unit
R _{thj-a}	Maximum Thermal Resistance, Junction-ambient ³	62.5	°C/W



Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-20	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-4.5\text{A}$	-	-	53	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-4.2\text{A}$	-	-	65	$\text{m}\Omega$
		$V_{\text{GS}}=-2.5\text{V}, I_{\text{D}}=-2.0\text{A}$	-	-	120	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-0.5	-	-1.2	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=-5\text{V}, I_{\text{D}}=-2.8\text{A}$	-	9	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=-20\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-1	uA
	Drain-Source Leakage Current ($T_j=55^\circ\text{C}$)	$V_{\text{DS}}=-16\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-10	uA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 12\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_{\text{D}}=-4.2\text{A}$	-	10.6	16	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=-16\text{V}$	-	2.32	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge		-	3.68	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ²	$V_{\text{DS}}=-15\text{V}$	-	5.9	-	ns
t_r	Rise Time	$I_{\text{D}}=-4.2\text{A}$	-	3.6	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=6\Omega$	-	32.4	-	ns
t_f	Fall Time	$V_{\text{GS}}=-10\text{V}$	-	2.6	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	740	1200	pF
C_{oss}	Output Capacitance		-	167	-	pF
C_{rss}	Reverse Transfer Capacitance		f=1.0MHz	-	126	-

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_{\text{S}}=-1.2\text{A}, V_{\text{GS}}=0\text{V}$	-	-	-1.2	V
t_{rr}	Reverse Recovery Time ²	$I_{\text{S}}=-4.2\text{A}, V_{\text{GS}}=0\text{V},$	-	27.7	-	ns
Q_{rr}	Reverse Recovery Charge	$dI/dt=100\text{A}/\mu\text{s}$	-	22	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
- 3.Surface mounted on 1 in² copper pad of FR4 board ; $156^\circ\text{C}/\text{W}$ when mounted on min. copper pad.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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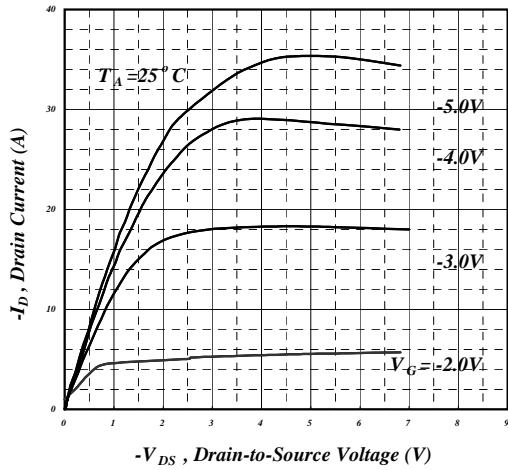


Fig 1. Typical Output Characteristics

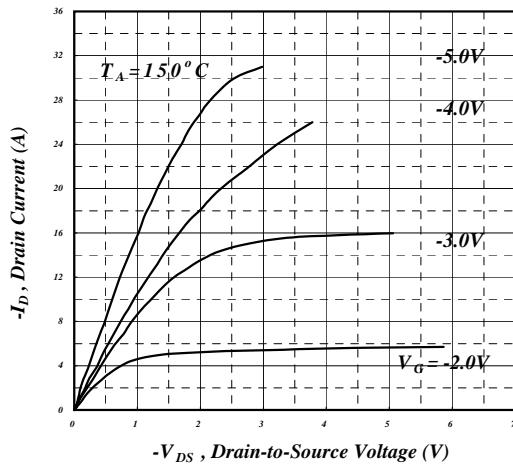


Fig 2. Typical Output Characteristics

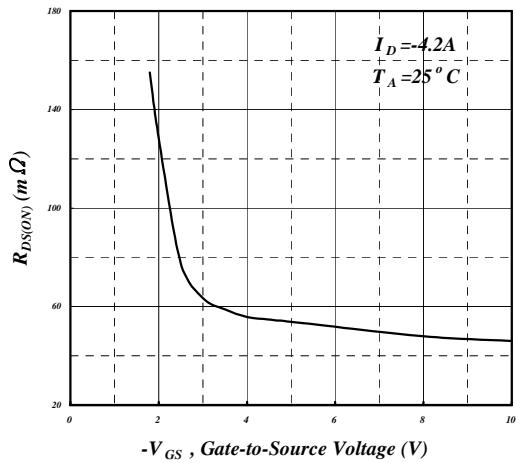


Fig 3. On-Resistance v.s. Gate Voltage

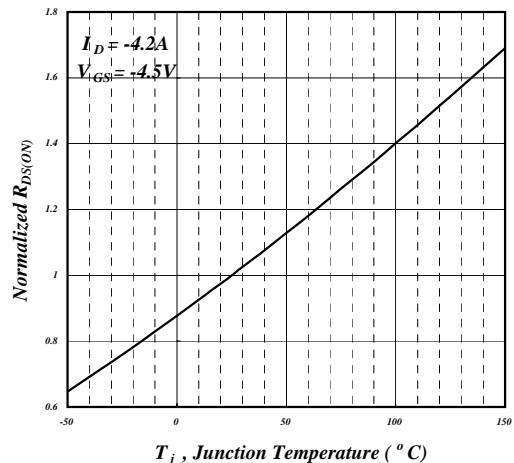


Fig 4. Normalized On-Resistance v.s. Junction Temperature

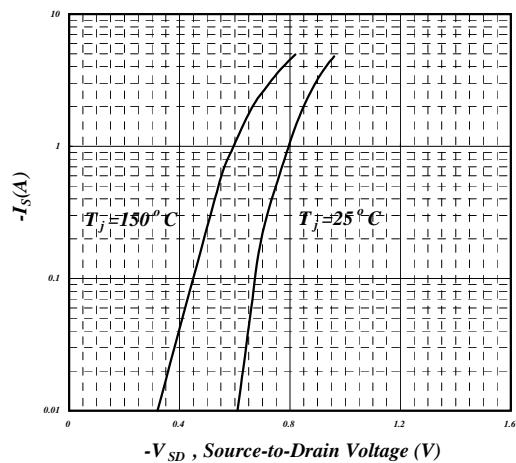


Fig 5. Forward Characteristic of Reverse Diode

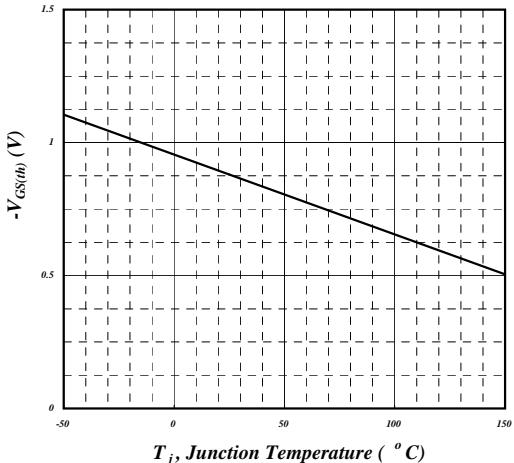


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

